


<b>Search Notes</b>  	<b>Application/Control No.</b>  10500562	<b>Applicant(s)/Patent Under Reexamination</b>  KAMEI, TOSHIO
	<b>Examiner</b>  Yeh, Eueng-nan	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
(382/173) text search - see search outputs	2007/12/31	/ey/
EAST text search - see search outputs	2007/12/27	/ey/
PALM inventor search - see search outputs	2007/12/27	/ey/
IEEE Xplore search - see search outputs	2008/01/02	/ey/
EAST text search - see search history list	2009.01.22	/ey/

INTERFERENCE SEARCH			
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